



<p style="text-align: center;">Searched</p> 	<p>Application/Control No.</p> <p>10766955</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>YAMASHITA ET AL.</p>
	<p>Examiner</p> <p>Rossoshek, Helen</p>	<p>Art Unit</p> <p>2825</p>


Class	SubClass	Date	Examiner
716	1,8,18	02/02/2006	HR
703	14,17,20,23,27	02/02/2006	HR
714	739,37	02/02/2006	HR
710	113	02/02/2006	HR
UPDATED	UPDATED	08/15/2006	HR

U.S. Patent and Trademark Office	Part of Paper No.: 20060815
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Interference Searched 	Application/Control No. 10766955	Applicant(s)/Patent Under Reexamination YAMASHITA ET AL.
	Examiner Rossoshek, Helen	Art Unit 2825

Class	SubClass	Date	Examiner
716	1,4,8,18	08/15/2006	HR
717	140,146	08/15/2006	HR

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Search Notes 	Application/Control No. 10766955	Applicant(s)/Patent Under Reexamination YAMASHITA ET AL.
	Examiner Rossoshek, Helen	Art Unit 2825

Notes	Date	Examiner
EAST - USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	02/02/2006	HR
IEEE	02/02/2006	HR
EAST (US-PGPUB), see search history printout	08/15/2006	HR
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